EasyA: Easy and effective way to generate pairwise test data

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ABSTRACT
Testing is a very important task to build error free software. As the resources and time to market is limited for a software product, it is impossible to perform exhaustive test i.e., to test all combinations of input data. To reduce the number of test cases in an acceptable level, it is preferable to use higher interaction level (t way, where t = 2). Pairwise (2- way or t = 2) interaction can find most of the software faults. This paper proposes a matrix based calculation for pairwise test data generation algorithm named EasyA to optimize the number of test cases. Java program has been used to test the performance of the algorithm. The performance is better than the existing algorithms/tools in terms of number of generated test cases and time consumption.

KEYWORDS:
Combinatorial interaction testing; Software testing; Pairwise testing' Test case generation

REFERENCES

1. Yingxia Cui, Longshu Li, Sheng Yao "A New strategy for pairwise test case generation" in proceedings of the third international Symposium on Intelligent Information Technology Application, NanChang, China, 2009

2. Y. Lei, R. Kacker, D.R. Kuhn, V. Okun, and J.Lawrence, "IPOG: A general strategy for t-way software testing," in proceedings of the 14th Annual IEEE International Conference and Workshops on the Engineering and Computer-Based Systems, Tucson, Arizona, 2007.

3. Mohammed I. Younis, Kamal Z. Zamli, Nor Ashidi Mat Isa "Algebraic Strategy to Generate Pairwise Test Set for Prime Number Parameters and Variables" in proceedings of the IEEE international conference on computer and information technology, Kuala Lumpur, Malaysia, 2008.

4. Xiang Chen, Qing Gu, Jingxian Qi, Daoxu Chen "Applying Particle Swarm optimization to Pairwise Testing" in proceedings of the 34th Annual IEEE Computer Software And Application Conference, Seoul, Korea, 2010.

5. Mohammad F. J. Klaib, Sangeetha Muthuraman, Noraziah Ahmad, and Roslina Sidek "A Tree Based Strategy for Test Data Generation and Cost Calculation for Uniform and Non-Uniform Parametric Values" in proceedings of the 10th IEEE international conference on computer and information technology, West Yorkshire, UK, 2010.